Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 501.37465C10	APPLICATION NO. TBD			
INFORMAT	ION DISCLOSURE STATEMENT BY APPLICANT	APPLICANT TANABE, et al.				
(Use s	everal sheets if necessary)	FILING DATE February 10, 2004	EXPECTED GROUP 2829			

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